

Search Notes

Application/Control No.

10/790,800

Examiner

John S. Chu

Applicant(s)/Patent under
Reexamination

TOMIKAWA ET AL.

Art Unit

1752

SEARCHED

Class	Subclass	Date	Examiner
430	191	8/2005	Sie
430	192		
430	193		
430	270.1		
430	326		
430	18		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner